

In the specification:

Replace the paragraph beginning at page 1, line 3 with the following rewritten paragraph:

**CROSS-REFERENCES TO RELATED APPLICATIONS**

This application is a continuation of application serial number 10/301,677, filed November 22, 2002, which is a continuation of application serial number 09/906,062, filed July 17, 2001, now U.S. Patent No. 6,509,965, which is a continuation of application serial number 09/624,502, filed July 24, 2000, now U.S. Patent No. 6,292,259, which is a continuation of application serial number 08/958,230, filed October 27, 1997, now U.S. Patent No. 6,118,525, which is a continuation-in-part of application serial number 08/399,962, filed March 16, 1995, now U.S. Patent No. 5,712,701. This application also claims priority from provisional application number 60/032,103, filed December 4, 1996.

In the claims:

**Please amend the claims as follows:**

Claims 1-29 (Cancelled).

Claim 30 (New): A system for distinguishing between particle defects and pit defects on a surface of a workpiece, the system comprising:

a light source arranged to project p-polarized light at an angle not parallel to the surface of the workpiece; and

a controller configured to classify a defect on the surface of the workpiece as a pit or particle based on a comparison of a first signal corresponding to light scattered from the surface of the workpiece in a direction generally normal to the surface of the workpiece and a second signal corresponding to light scattered from the surface of the workpiece in a direction away from the light source and offset from the direction generally normal to the surface of the workpiece.

Claim 31 (New): The system of claim 30 wherein the controller is configured to determine a ratio of the first signal and the second signal.

Claim 32 (New): The system of claim 31 wherein the controller is configured to compare the ratio to a predetermined value.

Claim 33 (New): The system of claim 32 wherein the controller classifies a defect as a particle if the ratio of the second signal to the first signal exceeds a threshold value.

Claim 34 (New): The system of claim 32 wherein the controller classifies a defect as a pit if the ratio of the first signal to the second signal exceeds a threshold value.

Claim 35 (New): A system for distinguishing between particle defects and pit defects on a surface of a workpiece, the system comprising:

a light source arranged to project p-polarized light at an angle not parallel to the surface of the workpiece; and

a controller configured to classify a defect on the surface of the workpiece as a pit or particle based on a comparison of a first signal corresponding to light scattered from the surface of the workpiece in a direction generally normal to the surface of the workpiece and a second signal corresponding to light scattered from the surface of the workpiece in a direction toward the light source and offset from the direction generally normal to the surface of the workpiece.

Claim 36 (New): The system of claim 35 wherein the controller is configured to determine a ratio of the first signal and the second signal.

Claim 37 (New): The system of claim 35 wherein the controller is configured to compare the ratio to a predetermined value.

Claim 38 (New): The system of claim 37 wherein the controller classifies a defect as a particle if the ratio of the second signal to the first signal exceeds a threshold value.

Claim 39 (New): The system of claim 37 wherein the controller classifies a defect as a pit if the ratio of the first signal to the second signal exceeds a threshold value.